

Notice of References Cited	Application/Control No. 10/606,226	Applicant(s)/Patent Under Reexamination WATANABE, HIDEAKI	
	Examiner Hiep Nguyen	Art Unit 2816	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,317,283	05-1994	Korhonen, Veijo S.	331/1A
	C	US-5,982,208	11-1999	Kokubo et al.	327/119
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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